



DMN2027LK3

Maximum Ratings @T_A = 25°C unless otherwise specified

Characteristic			Symbol	Value	Unit	
Drain-Source voltage			V _{DSS}	20	V	
Gate-Source voltage			V _{GS}	±12	V	
		(Note 3)		17.0		
Continuous Drain current	$V_{GS} = 10V$	$T_A = 70^{\circ}C \text{ (Note 3)}$	l _D	13.6	Α	
		(Note 2)		11.6		
Pulsed Drain current	ulsed Drain current $V_{GS} = 10V$ (Note 4)		I _{DM}	46.8	Α	
Continuous Source current (Body diode) (Note 3)			Is	11.9	Α	
Pulsed Source current (Body diode) (Note 4)			I _{SM}	46.8	A	

Thermal Characteristics @TA = 25°C unless otherwise specified

Characteristic	Symbol	Value	Unit		
	(Note 2)		4.18 33.44		
Power dissipation Linear derating factor	(Note 3)	P _D	8.9 71.4	W mW/°C	
	(Note 5)		2.14 17.1		
	(Note 2)		29.9		
Thermal Resistance, Junction to Ambient	(Note 3)	$R_{\theta JA}$	14.0	2011	
	(Note 5)		58.4	°C/W	
Thermal Resistance, Junction to Lead	(Note 6)	$R_{\theta JL}$	2.46		
Operating and storage temperature range	T _J , T _{STG}	-55 to 150	°C		

Notes:

- 2. For a device surface mounted on 50mm x 50mm x 1.6mm FR4 PCB with high coverage of single sided 2oz copper, in still air conditions; the device is measured when operating in a steady-state condition.
- 3. Same as note 2, except the device is measured at $t \le 10$ sec.
- Same as note 2, except the device is measured at t≤ 10 sec.
 Same as note 2, except the device is pulsed with D = 0.02 and pulse width 300 µs. The pulse current is limited by the maximum junction temperature.
 For a device surface mounted on 25mm x 25mm x 1.6mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions; the device is measured when operating in a steady-state condition.

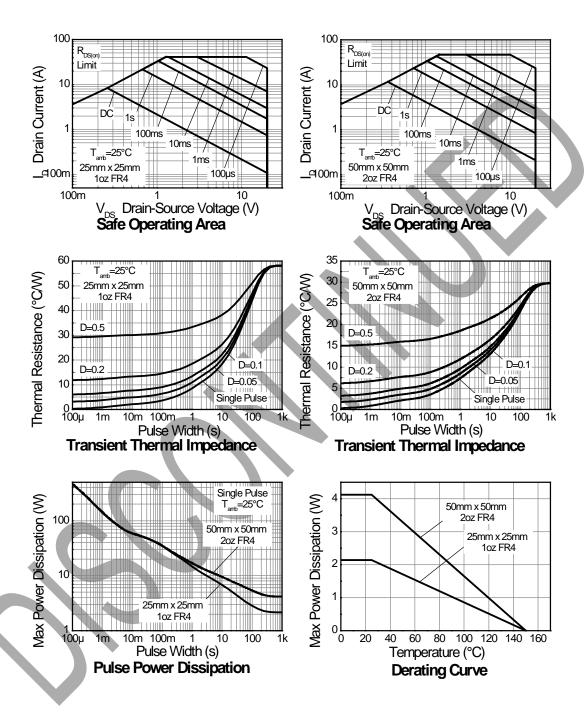
 6. Thermal resistance from junction to solder-point (at the end of the drain lead).







Thermal Characteristics







DMN2027LK3

Electrical Characteristics @T_A = 25°C unless otherwise specified

Characteristic	Symbol	Min	Тур	Max	Unit	Test Con	dition	
F CHARACTERISTICS iin-Source Breakdown Voltage BV _{DSS} 20 — V I _D = 250μA, V _{GS} = 0V								
Drain-Source Breakdown Voltage		20	_	_	V	$I_D = 250 \mu A, V_{GS} = 0$	V	
Zero Gate Voltage Drain Current		_	_	0.5	μА	V _{DS} = 20V, V _{GS} = 0\	/	
Gate-Source Leakage	I _{GSS}	_	_	±100	nA	V_{GS} = ±12 V , V_{DS} = $($)V	
ON CHARACTERISTICS								
Gate Threshold Voltage	V _{GS(th)}	0.6	_	2.0	V	$I_D=250\mu A,\ V_{DS}=V$	GS	
			— 0.027 • V _{GS} = 4.5V, I _D = 10	$V_{GS} = 10V, I_{D} = 20A$				
Static Drain-Source On-Resistance (Note 7)	R _{DS (ON)}	_		0.027	• .	V _{GS} = 4.5V, I _D = 10A		
				0.040		V _{GS} = 2.5V, I _D = 4A		
Forward Transconductance (Notes 7 & 8)	g _{fs}	_	31.7	_	S	V _{DS} = 15V, I _D = 10A		
Diode Forward Voltage (Note 7)	V_{SD}	_	0.89	1.0	V	I _S = 10A, V _{GS} = 0V		
Reverse recovery time (Note 8)	t _{rr}		121	-	ns	1 400 41/44 400	21 -	
Reverse recovery charge (Note 8)	Q _{rr}	_	583	_	nC	I _S = 10A, di/dt= 100A/μs		
DYNAMIC CHARACTERISTICS (Note 8)			•					
Input Capacitance	C _{iss}	_	857		pF		,	
Output Capacitance	Coss	_	177	-	pF	V _{DS} = 10V, V _{GS} = 0\ f= 1MHz	/	
Reverse Transfer Capacitance	C _{rss}		102		pF	TIE TIVILIZ		
Total Gate Charge	Qg	-	5.2	-	nC	V_{GS} = 2.5 V , I_D = 4 A		
Total Gate Charge	Qg	A	9.1		nC		V _{DS} = 10V	
Gate-Source Charge	Q _{gs}		1.9	_	nC	V _{GS} = 4.5V -I _D = 10A		
Gate-Drain Charge	Q_{gd}		3.2		nC			
Turn-On Delay Time (Note 9)	t _{D(on)}	_	5.4	_	ns	1		
Turn-On Rise Time (Note 9)	t _r	_	22.3	_	ns	V _{DD} = 10V, V _{GS} = 10	0V	
Turn-Off Delay Time (Note 9)	t _{D(off)}		18.7	_	ns	I_D = 10A, $R_G \cong 6.0\Omega$		
Turn-Off Fall Time (Note 9)	t _f		12.6	—	ns			

Notes:

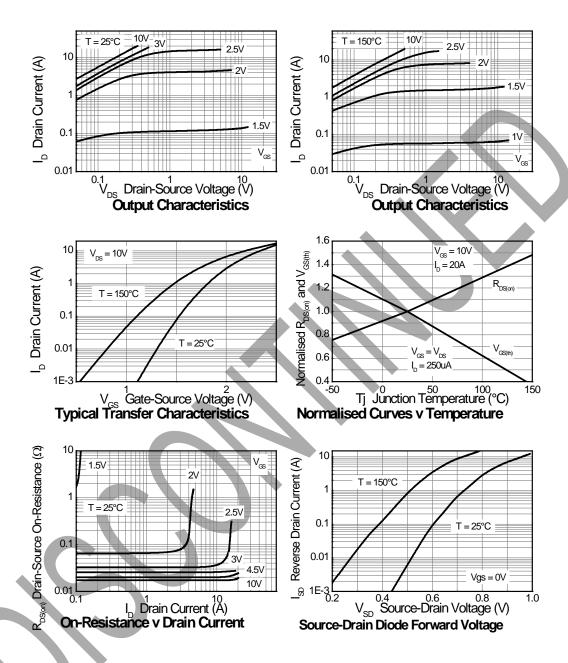
- Measured under pulsed conditions. Pulse width ≤ 300µs; duty cycle ≤ 2%
 For design aid only, not subject to production testing.
 Switching characteristics are independent of operating junction temperatures.





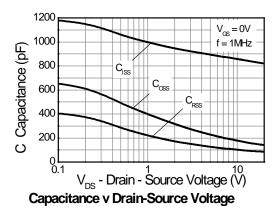


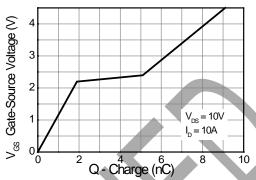
Typical Characteristics





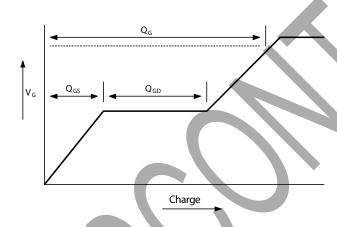
Typical Characteristics - continued

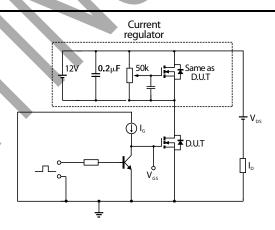




Gate-Source Voltage v Gate Charge

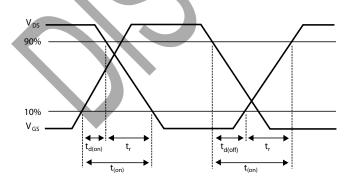
Test Circuits

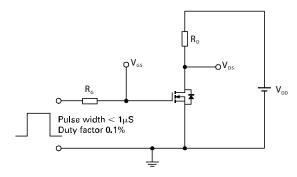




Basic gate charge waveform

Gate charge test circuit





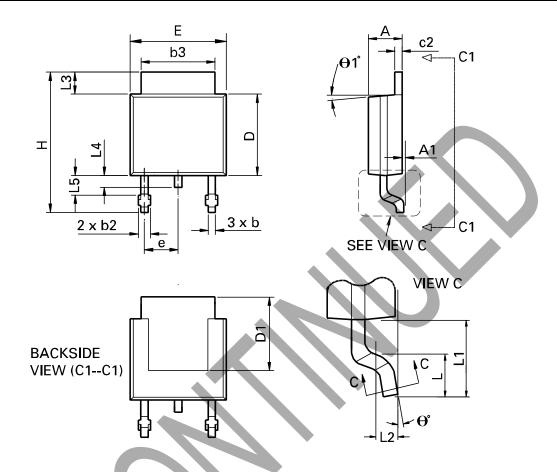
Switching time waveforms

Switching time test circuit





Package Outline Dimensions

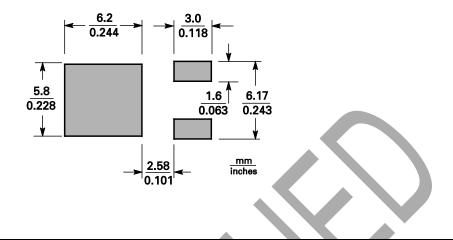


DIM	Inches		Millimeters		DIM	Inches		Millimeters	
	Min	Max	Min	Max		Min	Max	Min	Max
Α	0.086	0.094	2.18	2.39	e	0.090 BSC		2.29 BSC	
A 1	-	0.005	-	0.127	Н	0.370	0.410	9.40	10.41
b	0.020	0.035	0.508	0.89	L	0.055	0.070	1.40	1.78
b2	0.030	0.045	0.762	1.14	L1	0.108 REF		2.74 REF	
b3	0.205	0.215	5.21	5.46	L2	0.020 BSC		0.508 BSC	
C	0.018	0.024	0.457	0.61	L3	0.035	0.065	0.89	1.65
c2	0.018	0.023	0.457	0.584	L4	0.025	0.040	0.635	1.016
D	0.213	0.245	5.41	6.22	L5	0.045	0.060	1.14	1.52
D1	0.205	-	5.21	-	•1°	0°	10°	0°	10°
E	0.250	0.265	6.35	6.73	• °	0°	15°	0°	15°
E1	0.170	-	4.32	-	-	-	-	-	-





Suggested Pad Layout



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